

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 501.37465C10	APPLICATION NO. TBD
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		APPLICANT TANABE, et al.	
		FILING DATE February 10, 2004	EXPECTED GROUP 2829

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
V4	AA	2001/0042344	11/22/2001	Ohmi, et al.		
V4	AB	5,959,329	9/28/1999	Tomita, et al.		

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation/ Abstract	
						Yes	No
V4	AC	08-213379	8/20/1996	Japan		X	
V4	AD	11-067747	3/9/1999	Japan		X	
	AE	11-074264	3/16/1999	Japan		X	
	AF	10-284484	10/23/1998	Japan		X	
	AG	11-162971	6/18/1999	Japan		X	
	AH	11-162970	6/18/1999	Japan		X	
	AI	11-204517	7/30/1999	Japan		X	
	AJ	11-186255	7/9/1999	Japan		X	
	AK	11-135492	5/21/1999	Japan		X	
	AL	9-153489	6/10/1997	Japan		X	
	AM	11-233508	8/27/1999	Japan		X	
	AN	11-186248	7/9/1999	Japan		X	
	AO	07-297201	11/10/1995	Japan		X	
	AP	07-297181	11/10/1995	Japan		X	
V4	AQ	07-273101	10/20/1995	Japan		X	
V4	AS	9-148461	6/6/1997	Japan		X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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Examiner <i>V. Yeager</i>	Date Considered 06/09/05

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U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
V4	AA	6,037,273	3/00	Gronet, et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation /Abstract	
							Yes	No
V4	AM	7-86264	3/95	Japan				X
↑	AN	7-193059	7/95	Japan			X	
	AO	5-114740	5/93	Japan			X	
	AP	7-321102	12/95	Japan			X	
	AQ	60-107840	6/85	Japan			X	
	AR	5-141871	6/93	Japan			X	
	AS	5-144804	6/93	Japan			X	
	AT	6-120206	4/94	Japan			X	
↓	AU	59-132136	7/84	Japan			X	
V4	AV	WO/9728085	7/97	PCT			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	AW	
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Examiner <i>V. Yeisner</i>	Date Considered <i>06/09/05</i>	

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		FILING DATE February 2, 2004	EXPECTED GROUP 2829

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclasses	Filing Date
VY	AA	6,362,086	3-26-02	Weimer, et al.		
↑	AB	5,751,025	5/98	Heminger, et al.		
	AC	4,139,658	2/79	Cohen, et al.		
	AD	5,693,578	12/97	Nakanishi, et al.		
	AE	5,880,041	3/99	Ong		
	AF	5,851,892	12/98	Lojek, et al.		
	AG	5,840,368	11/98	Ohmi		
↓	AH	5,786,263	7/98	Perera		
VY	AI	6,239,041	5/01	Tanabe, et al.		

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclasses	Translation/Abstract	
						Yes	No
VY	AJ	7-115069	5-2-95	Japan		X	
↑	AK	9-172011	6/97	Japan		X	
	AL	6-333918	12/94	Japan		X	
	AM	7-10935	2/95	Japan			X
	AN	7-115069	5/95	Japan			X
	AO	5-152282	6/93	Japan		X	
	AP	6-163517	6/94	Japan		X	
↓	AQ	6-115903	4/94	Japan		X	
VY	AR	8-111449	4/96	Japan			X

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	AS	Nakamura, et al., "Proceedings of the 45 th Symposium on Semiconductors and Integrated Circuits Technology", December 1-2, 1993. (full translation)				
VY	AT	Tanabe, et al., PG Pub: US 2002/0004315 A1, 1/10/02				
↑	AU	Tanabe, et al., PG Pub: US 2002/0019149 A1, 2/14/02				
	AV	Tanabe, et al., PG Pub: US 2001/0009813 A1, 7/26/01				
	AW	Tanabe, et al., PG Pub: US 2001/0010975 A1, 8/2/01				
↓	AX	Tanabe, et al., PG Pub: US 2001/0024870 A1, 9/27/01				
VY	AY	Tanabe, et al., PG Pub: US 2001/0006853 A1, 7/5/01				
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V. Y. Lee				06/09/05		

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		FILING DATE February 10, 2004	EXPECTED GROUP 2829

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
VY	AA	4,374,116	2/15/1983	Chuang, et al.		
VY	AB	4,119,706	10/10/1978	Rogers		
VY	AC	3,857,927	12/31/1974	Henrie		

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation/A bstract	
						Yes	No
VY	AD	5-19746	3/12/1993	Japan			
	AE	63-85630	6/4/1988	Japan			
	AF	57-49895	3/24/1982	Japan			
	AG	58-19599	2/4/1983	Japan			
	AH	57-82102	5/22/1982	Japan		X	
	AI	55-041805	3/24/1980	Japan		X	
	AJ	55-003820	1/11/1980	Japan		X	
	AK	0 666 237	08/09/1995	EP			
	AL	09-148315	6/6/1997	Japan		X	
VY	AM	09-090092	4/4/1997	Japan		X	
	AN						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AO	Japanese Patent Office Action mailed May 16, 2000 for No. 3110456 with English translation
Examiner	V. Y. [Signature]
Date Considered	08/09/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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